

# EUROPEAN PATENT OFFICE

## Patent Abstracts of Japan

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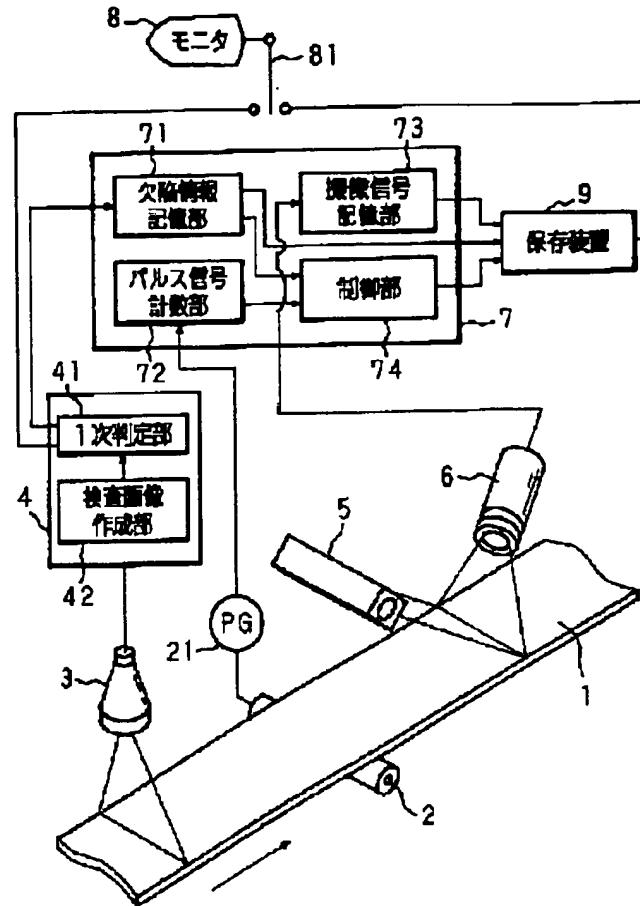
APPLICATION DATE : 03-03-98  
 APPLICATION NUMBER : 10051069

APPLICANT : SUMITOMO METAL IND LTD;

INVENTOR : KISHI KAZUHIKO;

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TITLE : DEVICE AND METHOD FOR  
 INSPECTING SURFACE DEFECT



**ABSTRACT :** PROBLEM TO BE SOLVED: To enhance the precision of secondary judgement of surface defects.

**SOLUTION:** Image pickup signals from a scan camera 6 are always input to an image pickup signal storage part 73 to form two-dimensional images. A control part 74 extracts portions of the two-dimensional images corresponding to surface defects detected in primary judgement as defective images at a timing when a unit area where the surface defects in primary judgement exist passes through an image pickup position of the scan camera 6. The extracted defective images are reserved as database in a reservoir 9. A monitor 8 usually shows the results of the primary judgement but shows the defective images in respect to the specified surface defects for secondary judgement when instructions for secondary judgement are given by an operator.

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